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Applicati n No.	Applicant(s)	
09/842,694	KOBAYASHI ET AL.	
Examiner	Art Unit	
Johannes P Mondt	2826	

	SEARCHED		
Class	Subclass	Date	Examiner
257	414	6/13/2004	JPM
257	431-432	6/13/2004	JPM
257	448	6/13/2004	JPM
250	370.01	6/13/2004	JPM
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SEARCH I (INCLUDING SEAR	NOTES CH STRATEGY)
	DATE	EXMR
East data bases and IEEE	6/13/2004	JPM